

Drafts

- BRS:
- BRS:
- BRS:
- BRS: knall
- BRS: 19 21 23
- BRS: 32with 33

 Pending Active

- L1: (515589) drain
- L2: (1360957) test
- L3: (2035133) (trench\$2 recess\$4) groove
- L4: (1060780) select
- L5: (729094) transistor tft
- L6: (1897154) vertical
- L7: (20720) L5 near2 (L6 L4 L3)
- L8: (244) L7 same L2
- L9: (3548) L2 near12 L1
- L10: (7) L9 same L8

 Failed Saved

S2: (1) 09/948877

[S] [U] [P] [J] [D]

Search special: [DA]

View

Highlight all hot items:

L9 same L8

02/24/2005

U#	Inventor	Document	Issue P	Title	Current Curr	X	Retrieval	S	C	P	S	T	Image	Do	P
1	<input checked="" type="checkbox"/> Wang, Jiaoguo et al.	US 20040208055 A1	2004 10210	Methods and circuits for testing programmability of a semiconductor memory cell and memory array testing method	365/182			<input checked="" type="checkbox"/>	US 20040208055						
2	<input checked="" type="checkbox"/> Pio; Federico et al.	US 6128219 A	2000 10033	Nonvolatile memory test structure and nonvolatile memory reliability test method	365/185.05.09	365/185.05; 365/185.2		<input checked="" type="checkbox"/>	US 6128219						
3	<input checked="" type="checkbox"/> Kowalski, Bernhard et al.	US 20050040309 A1	2005 02242	Test structure for improved vertical memory arrays	257/48			<input checked="" type="checkbox"/>	US 20050040309						
4	<input checked="" type="checkbox"/> Kamoshida, Masahiro	US 2005000201063	2005 01063	Shared sense amplifier scheme semiconductor memory device and	365/201			<input checked="" type="checkbox"/>	US 2005000201063						